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File No.: 14836-8US-2 AD/mb

Montreal, Canada March 9, 2005

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Application of:

plicant:

MICROBRIDGE TECHNOLOGIES INC.

Serial No.:

10/796,420

Filed:

March 10, 2004

Title:

METHOD FOR TRIMMING RESISTORS

Group Art Unit:

3742

Examiner:

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Agent of Record:

Alexandra Daoud Tel: (514) 847-4333

MAIL STOP - AMENDMENTS

U.S. Patent and Trademark Office

P.O. Box 1450

Alexandria, Virginia 22313-1450

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SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT PRIOR TO FIRST OFFICE ACTION

Sir:

Pursuant to the duty of disclosure under 37 CFR 1.56, copies of the references listed on the attached PTO Form SB08A/B are submitted herewith.

In accordance with 37 CFR 1.97(h), the submission of the present information is not to be construed as an admission that such information is, or is considered to be material to patentability.

The Examiner is kindly requested to consider these references during the examination of the above-identified application, making the references of record, and to return an initialed copy of the SB08A/B Form to the below-signed agent.

Respectfully submitted,

MICROBRIDGE TECHNOLOGIES INC.

By:

Alexandra Daoud, Registration No. 55,992

OGILVY RENAULT

Customer Number 020988

Enc.: Copies of references cited therein

2 sets of SB08A/B Form

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			CLOSURE	Complete if Known		
		_	THE WILLIAM	Application Number	10/796, 420	
INF	ORMATIO	N DIS	CLOSURE	Filing Date	March 10, 2004	
STA	ATEMENT	BY A	PPLICANT	First Named Inventor	Oleg GRUDIN et al.	
				Art Unit	3742	
	(use as many sh	eets as n	ecessary)	Examiner Name	(unknown)	
Sheet	1	of	3	Attorney Docket Number	14836-8US-2 AD/mb	

	#U.S. PATENT DOCUMENTS							
Examiner Initials*	Cite No. ¹	Document Number Number – Kind Code ² (if known)	Publication Date MM-DD-YYYY	Name of Patentee or Applicant of Cited Document	Pages, Columns, Lines Where Relevant Passages or Relevant Figures Appear			
		US-6,097,276	Aug. 1, 2000	Van Den Broek et al.				
		US-5,844,122	Dec. 1, 1998	Kato				
		US-5,635,893	Jun. 3, 1997	Spraggins et al.				
		US-5,493,148	Feb. 20, 1996	Ohata et al.				
		US-5,460,040	Oct. 24, 1995	Tada et al.				
		US-4,902,959	Feb. 20, 1990	Brokaw				
		US-5,757,264	May 26, 1998	Petit				
		US-4,717,886	Jan. 5, 1988	Davis et al.				
		US-4,683,442	Jul.28, 1987	Vyne				
		US-4,606,781	Aug. 19, 1986	Vyne				
		US-5,110,758	May 5, 1992	Baskett				
		US-5,563,549	Oct. 8, 1996	Shieh				
		US-						
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	FOREIGN PATENT DOCUMENTS									
Examiner	Cite	Foreign Patent Document	Publication Date	Name of Patentee or	Pages, Columns, Lines Where Relevant Passages					
Initials*	No.1	Country Code3 - Number4 - Kind Code5 (if known)	MM-DD-YYYY	Applicant Of Cited Document	or Relevant Passages or Relevant Figures Appear	T ⁶				
		WO 00/21196	Apr. 13, 2000	Honeywell Inc.						
	-					+				

Examiner	Date	
Signature	Considered	

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. ¹ Applicant's unique citation designation number (optional). ² See Kinds Codes of USPTO Patent Documents at www.uspto.gov or MPEP 901.04 ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST. 16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is

This collection of information is required by 37 CFR 1.97 and 1.98. The information is required to obtain or retain a benefit by the public which is to file (and by the USPTO to process) an application. Confidentiality is governed by 35 U.S.C. 122 and 37 CFR 1.14. This collection is estimated to take 2 hours to complete, including gathering, preparing, and submitting the completed application form to the USPTO. Time will vary depending upon the individual case. Any comments on the amount of time you require to complete this form and/or suggestions for reducing this burden, should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, U.S. Department of Commerce, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, P.O. Box 1450, Alexandria VA 22313-1450.

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Substitute f	or form 1449PTO			Complete if Known		
				Application Number	10/796, 420	
INF	ORMATION	I DIS	CLOSURE	Filing Date	March 10, 2004	
ST/	ATEMENT E	BY A	PPLICANT	First Named Inventor	Oleg GRUDIN et al.	
				Art Unit	3742	
	(use as many she	ets as n	ecessary)	Examiner Name	(unknown)	
Sheet	2	of	3	Attorney Docket Number	14836-8US-2 AD/mb	

		NON PATENT LITERATURE DOCUMENTS							
Examiner Initials*									
		Constant Voltage Trimming of Heavily Doped Polysilicon Resistors, Japan Journal Appl. Phys. Vol. 34, Part 1, No. 1, January 1995, pp. 48-53.							
		Pulse Current Trimming of Polysilicon Resistors, Transactions of Electron Devices, IEEE, Vol. 42, N° 4, April 1995, pp. 689-695.							
		Change in Temperature Coefficient of Resistance of Heavily Doped Polysilicon Resistors Caused by Electrical Trimming, Japan Journal Appl. Phys, Vol. 35, Part 1, No. 8, August 1995, pp. 4209-4215.							
		Theory and Application of Polysilicon Resistor Trimming, Solid-State Electronics, Vol. 38, N° 11, 1995, pp. 1861-1869.							
		Electrical Trimming of Ion-Beam Sputtered Polysilicon Resistors by High Current Pulses, IEEE Transactions on Electron Devices, Vol. 41, No. 8, August 1994, pp. 1429-1434.							
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		A Monolithic 14Bit D/A Converter Fabricated with a New Trimming Technique (DOT), IEEE, Journal of Solid-State Circuits, Vol. SC-19, N° 5, October 1984, pp. 802-807.							
		Precision Electrical Trimming of Very Low TCR Poly-SiGe Resistors, IEEE Electron Device Letters, Bol. 21, No. 6, June 2000, pp. 283-286.							
		1/f Noise Transformation that Accompanies the Trimming of Polycrystalline Silicon Layers, Solid State Phenomena, Vols. 51-52 (1996) Scitec Publications, Switzerland, pp. 391-396.							
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Examine		Date	
Signatur	ı	Considered	

^{*}EXAMINER if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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ST/	ATEMENT I	BY A	PPLICANT	First Named Inventor	Oleg GRUDIN et al.	
				Art Unit	3742	
	(use as many sh	eets as n	ecessary)	Examiner Name	(unknown)	
Sheet	3	of	3	Attorney Docket Number	14836-8US-2 AD/mb	

	NON PATENT LITERATURE DOCUMENTS						
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published	T ²				
		CMOS-Compatible High-Temperature Micro-Heater: Microstructure Release and Testing, Can. J. Elect & Comp. Eng., Vol. 25, No. 1, January 2000, pp. 002-006.					
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		Electrical and Optical Characteristics of Vacuum-Sealed Polysilicon Microlamps, Carlos H. Mastrangelo et al., IEEE Transactions on Electron Devices, Vol. 39, N° 6, June 1992, pp. 1363-1374.					
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Examiner	Date	
Signature	 Considered	

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